

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/824,123	HAN ET AL.	
Examiner		Art Unit		Page 1 of 1
Michael La Villa		1775		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0002221 A1	01-2004	O'Donnell et al.	438/710
*	B	US-2002/0012791 A1	01-2002	Morita et al.	428/336
*	C	US-2001/0003271 A1	06-2001	Otsuki, Hayashi	118/723.001
*	D	US-6,776,873 B1	08-2004	Sun et al.	156/345.41
*	E	US-6,447,937 B1	09-2002	Murakawa et al.	428/696
*	F	US-6,287,644 B1	09-2001	Jackson et al.	427/566
*	G	US-5,807,613 A	09-1998	Aguero et al.	427/528
*	H	US-3,754,903 A	08-1973	Goward et al.	420/443
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11-229142	08-1999	JP	Takeuchi et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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